



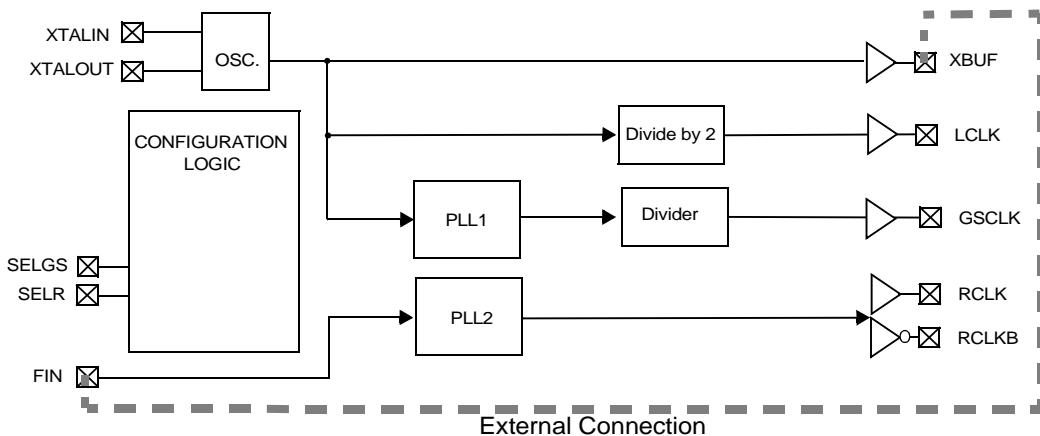
CYPRESS

CY22312

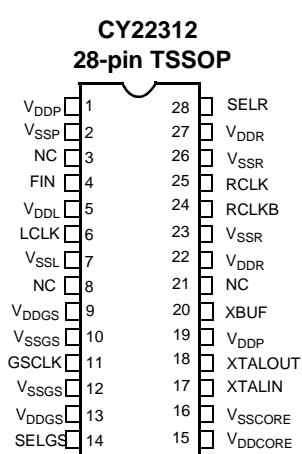
## Two-PLL Clock Generator with Direct Rambus™ (Lite) Support

Features	Benefits
<b>Two integrated phase-locked loops</b>	High-performance PLL tailored for multimedia applications
<b>Ultra-accurate PLLs</b>	High performance even with difficult multiplier ratios
<b>Compatible crystal load capacitors</b>	Identical oscillator circuit to CY24141
<b>Direct Rambus™ clock support</b>	One pair of differential output drivers, identical specification to CY2212
<b>Two input selects</b>	Selectable 54.0/53.946 MHz output and 300/400 MHz Rambus® output
<b>3.3V core, 3.3V and 2.5V outputs</b>	Supports SONY output voltage requirements
<b>28-pin TSSOP package</b>	Industry-standard packaging saves on board space

### Logic Block Diagram



### Pin Configuration



### Frequency Select Tables

GSSEL	PPM	GSCLK	Unit
0	0	54	MHz
1	-1.000	53.94605395	MHz
RSEL	PPM	RCLK, RCLKB	Unit
0	0	294.912	MHz
1	0	393.216	MHz

### Pin Summary

Name	Pin Numbers	Description
V <sub>DDP</sub>	1, 19	Power Supply for FIN, XBUF, and Crystal Oscillator
V <sub>SSP</sub>	2	Ground
NC	3, 8, 21	No Connect (Reserved for Test Mode)
FIN	4	18.432-MHz input, must be externally connected to XBUF
V <sub>DDL</sub>	5	Power Supply for LCLK
LCLK	6	9.216-MHz output, FIN/2
V <sub>SSL</sub>	7	Ground
V <sub>DDGS</sub>	9, 13	Power Supply for GSCLK
V <sub>SSGS</sub>	10, 12	Ground
GSCLK	11	53.946-MHz/54-MHz output, frequency selectable with SELGS pin
SELGS	14	GSCLK Select Input, Internal Pull-Down Resistor, Referenced to V <sub>DDCORE</sub>
V <sub>DDCORE</sub>	15	Power Supply for Core
V <sub>SSCORE</sub>	16	Ground
XTALIN	17	Reference Crystal Input
XTALOUT	18	Reference Crystal Output
XBUF	20	Buffered Reference Output, must be externally connected to FIN
V <sub>DDR</sub>	22, 27	Power Supply for RCLK and RCLKB
V <sub>SSR</sub>	23, 26	Ground
RCLKB	24	Direct Rambus output (complement)
RCLK	25	Direct Rambus output
SELR	28	Direct Rambus PLL Multiplier Select Input, Internal Pull-Up Resistor, Referenced to V <sub>DDR</sub>

## Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

Supply Voltage ..... -0.5V to +4.0V

DC Input Voltage ..... -0.5V to + (V<sub>DD</sub> + 0.5V)

Storage Temperature ..... -65°C to +125°C

Static Discharge Voltage

(per MIL-STD-883, Method 3015) ..... 2000V

Latch up (per JEDEC 17) .....  $\geq \pm 200$  mA

## Operating Conditions<sup>[1]</sup>

Parameter	Description	Min.	Typ	Max.	Unit
V <sub>DDR</sub> , V <sub>DDCORE</sub> , V <sub>DDP</sub>	Supply Voltage for Core, Crystal Oscillator, and 3.3V outputs	3.15	3.45	3.6	V
V <sub>DDGS</sub> , V <sub>DDL</sub>	Supply Voltage for 2.5V outputs	2.25	2.5	2.75	V
T <sub>A</sub>	Operating Temperature, Ambient	0		+70	°C
C <sub>LOAD_OUT</sub>	Max. Load Capacitance, CMOS outputs			15	pF
f <sub>REF</sub>	External Reference Crystal		18.432		MHz

## Electrical Characteristics

Parameter	Description	Conditions	Min.	Typ.	Max.	Unit
I <sub>OH</sub>	Output High Current, 3.3V outputs <sup>[2]</sup>	V <sub>OH</sub> = V <sub>DD</sub> - 0.5, V <sub>DD</sub> = 3.3V	12	24		mA
	Output High Current, 2.5V outputs <sup>[2]</sup>	V <sub>OH</sub> = V <sub>DD</sub> - 0.5, V <sub>DD</sub> = 2.5V	8	16		mA
I <sub>OL</sub>	Output Low Current, 3.3V outputs <sup>[2]</sup>	V <sub>OL</sub> = 0.5V, V <sub>DD</sub> = 3.3V	12	24		mA
	Output Low Current, 2.5V outputs <sup>[2]</sup>	V <sub>OL</sub> = 0.5V, V <sub>DD</sub> = 2.5V	8	16		mA
C <sub>XTAL</sub>	Crystal Load Capacitance <sup>[2]</sup>	Total effective load of internal load caps		12.9		pF
C <sub>LOAD_IN</sub>	Input Pin Capacitance <sup>[2]</sup>	Except crystal pins		7		pF
V <sub>IH</sub>	HIGH-Level Input Voltage	CMOS levels, % of referenced power supply	70%			V <sub>DD</sub>
V <sub>IL</sub>	LOW-Level Input Voltage	CMOS levels, % of referenced power supply			30%	V <sub>DD</sub>
R <sub>I_GS</sub>	SELGS Input Resistor	Pull-down resistor on SELGS	80	100	135	kΩ
R <sub>I_R</sub>	SELR Input Resistor	Pull-up resistor on SELR	10		100	kΩ
I <sub>DD</sub>	Total Power Supply Current	Sum of all supply currents			120	mA

## Direct Rambus Electrical Characteristics<sup>[2]</sup>

Parameter	Description	Min.	Max.	Unit.
V <sub>CM</sub>	Differential output common-mode voltage	1.35	1.75	V
V <sub>X</sub>	Differential output crossing-point voltage	1.25	1.85	V
V <sub>COS</sub>	Output Voltage swing (p-p single-ended) <sup>[3]</sup>	0.4	0.7	V
V <sub>COH</sub>	Output high voltage		2.1	V
V <sub>COL</sub>	Output low voltage	1.0		V
r <sub>OUT</sub>	Output dynamic resistance (at pins) <sup>[4]</sup>	12	50	Ω

**Notes:**

1. Unless otherwise noted, Electrical and Switching Characteristics are guaranteed across these operating conditions.
2. Guaranteed by design, not 100% tested
3. V<sub>COS</sub> = V<sub>OH</sub> - V<sub>OL</sub>.
4. r<sub>OUT</sub> = Δ V<sub>O</sub> / Δ I<sub>O</sub>. This is defined at the output pins, not at the measurement point of Figure 12.

## Switching Characteristics<sup>[2]</sup>

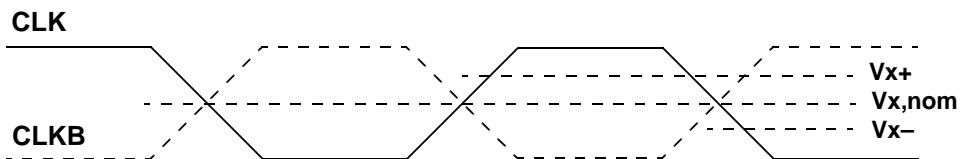
Parameter	Description	Conditions	Min.	Typ.	Max.	Unit
F <sub>PPM</sub>	Frequency Error	Part to Part, does not include PCB variation <sup>[5]</sup>		±5	±10	PPM
		Over commercial temperature range <sup>[6]</sup>		±2	±5	PPM
DC	Output Duty Cycle	Duty cycle for all outputs, measured at V <sub>DD</sub> /2	45%	50%	55%	
t <sub>3</sub>	Rising Edge Slew Rate	CMOS clock rise time, 20% to 80% of V <sub>DD</sub>	0.75	1.4		V/ns
t <sub>4</sub>	Falling Edge Slew Rate	CMOS clock fall time, 20% to 80% of V <sub>DD</sub>	0.75	1.4		V/ns
t <sub>CR</sub> , t <sub>CF</sub>	Rise and Fall times	RCLK rise and fall time, 20% to 80% of V <sub>DD</sub>	160		400	ps
t <sub>CR-CF</sub>	Rise and Fall difference <sup>[7]</sup>	RCLK rise and fall time difference, 20% to 80% of V <sub>DD</sub>			100	ps
t <sub>5</sub>	Lock Time	PLL Lock Time from Power-up		1.0	3	ms

## Jitter Specifications<sup>[2]</sup>

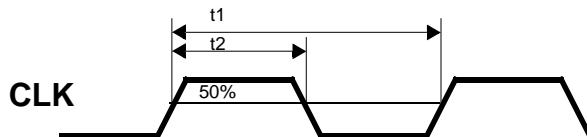
Parameter	Description	Conditions	Typ.	Max.	Unit
t <sub>6_XBUF</sub>	XBUF jitter <sup>[2]</sup>	Cycle-Cycle Jitter - 18.432 MHz		250	ps
t <sub>6_LCLK</sub>	LCLK jitter <sup>[2]</sup>	Cycle-Cycle Jitter - 9.216 MHz		250	ps
t <sub>6_GSCLK</sub>	GSCLK jitter <sup>[2]</sup>	Cycle-Cycle Jitter - 54 MHz, V <sub>DDGS</sub> = 2.25V - 2.75V		250	ps
		Cycle-Cycle Jitter - 53.946 MHz, V <sub>DDGS</sub> = 2.25V - 2.75V		250	ps
t <sub>7_XBUF</sub>	XBUF 1000 cycle jitter <sup>[2]</sup>	1000 Cycle-Cycle Jitter - 18.432 MHz		250	ps
t <sub>7_LCLK</sub>	LCLK 1000 cycle jitter <sup>[2]</sup>	1000 Cycle-Cycle Jitter - 9.216 MHz		250	ps
t <sub>7_GSCLK</sub>	GSCLK 1000 cycle jitter <sup>[2,8]</sup>	1000 Cycle-Cycle Jitter - 54 MHz, V <sub>DDGS</sub> = 2.25V - 2.75V		400	ps
		1000 Cycle-Cycle Jitter - 53.946 MHz, V <sub>DDGS</sub> = 2.25V - 2.75V		400	ps
t <sub>8</sub>	RCLK 1-6 cycle jitter <sup>[2,9]</sup>	Cycle-Cycle Jitter, 1-6 Cycles, 400 MHz		100	ps
		Cycle-Cycle Jitter, 1-6 Cycles, 300 MHz		140	ps
t <sub>9</sub>	RCLK Long-term jitter <sup>[2,10]</sup>	Long-term Jitter, 400 MHz		300	ps
		Long-term Jitter, 300 MHz		400	ps
t <sub>10</sub>	RCLK duty cycle error <sup>[2,11]</sup>	Cycle-Cycle Duty Cycle Error, 400 MHz		50	ps
		Cycle-Cycle Duty Cycle Error, 300 MHz		70	ps

**Notes:**

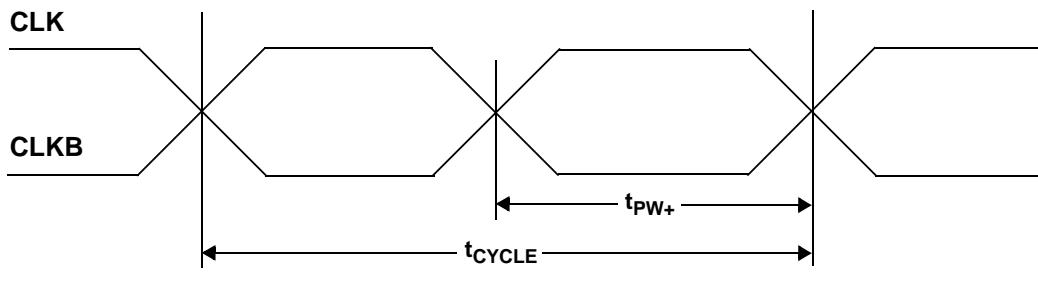
5. Tested across three lots on same board, PCB boards can vary more than ± 5 PPM.
6. Crystal should not be heated for this test, only IC.
7. Measured on same pin of a single device.
8. ± 4 Sigma, V<sub>DD</sub> = 3.3V.
9. Output short-term jitter specification is peak-to-peak and defined in *Figure 13*.
10. RCLK Long Term jitter shown in *Figure 9*.
11. RCLK Duty Cycle Error shown in *Figure 10*.



**Figure 1. RCLK Crossing Point Voltage**

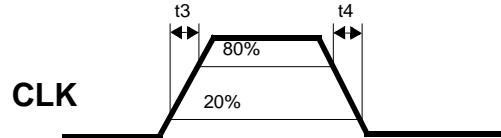


**Figure 2. CMOS Duty Cycle Definition**

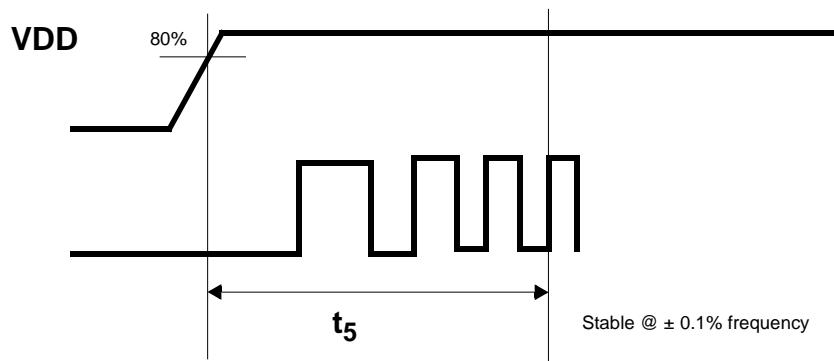


$$DC = \frac{t_{PW+}}{t_{CYCLE}}$$

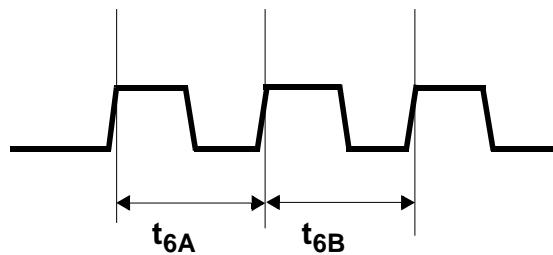
**Figure 3. RCLK Duty Cycle Definition**



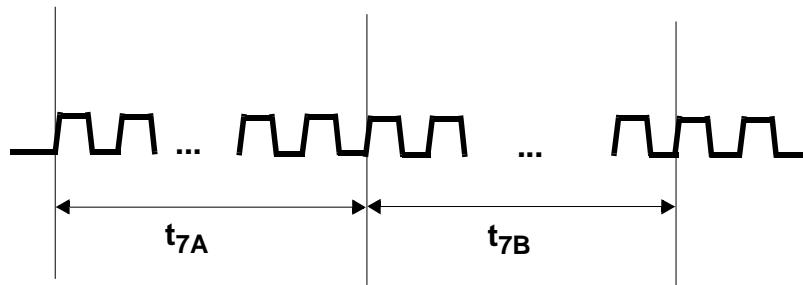
**Figure 4. Output Rise and Fall Time Definitions**



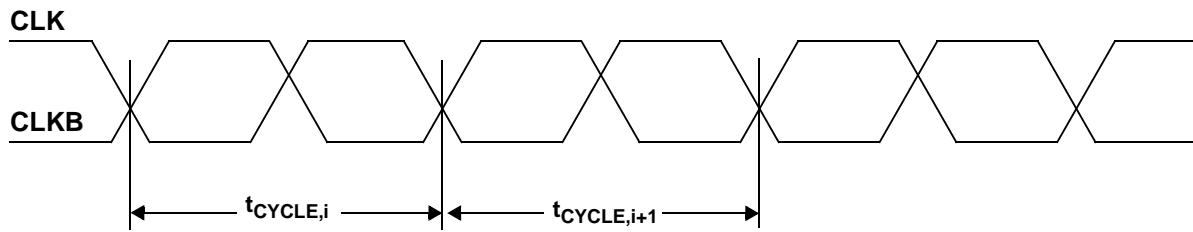
**Figure 5. PLL Lock Time**



**Figure 6. Cycle-to-Cycle Jitter**

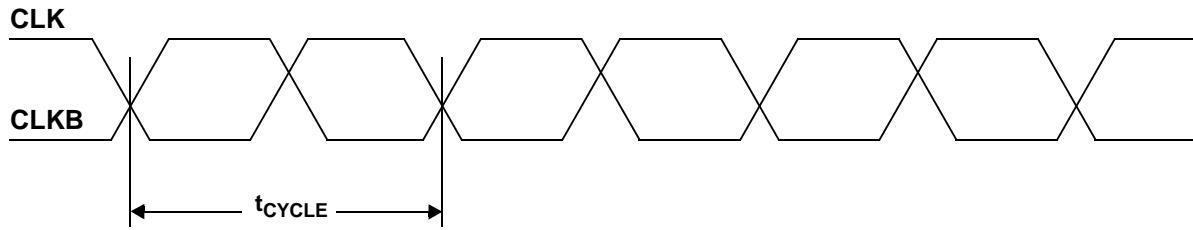


**Figure 7. 1000 Cycle Jitter**



$t_8 = t_{CYCLE,i} - t_{CYCLE,i+1}$  over 10000 consecutive cycles

**Figure 8. RCLK Cycle-to-Cycle Jitter**



$t_9 = t_{CYCLE,max} - t_{CYCLE,min}$  over 10000 cycles

**Figure 9. RCLK Long-term Jitter**

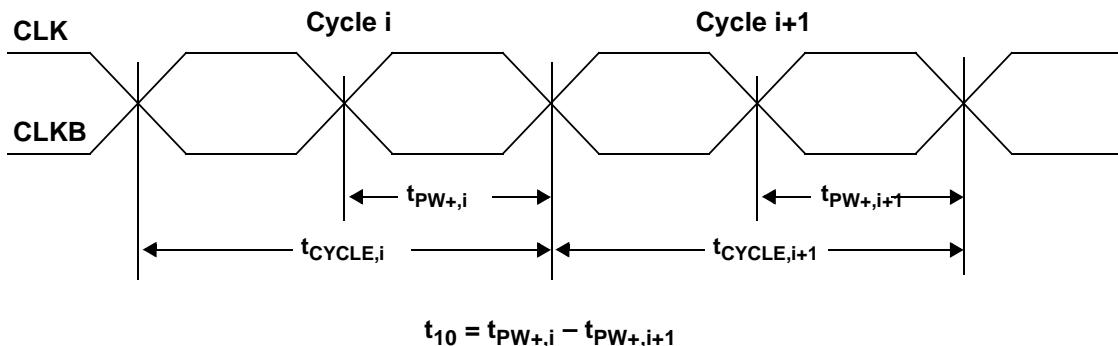


Figure 10. RCLK Duty Cycle Error

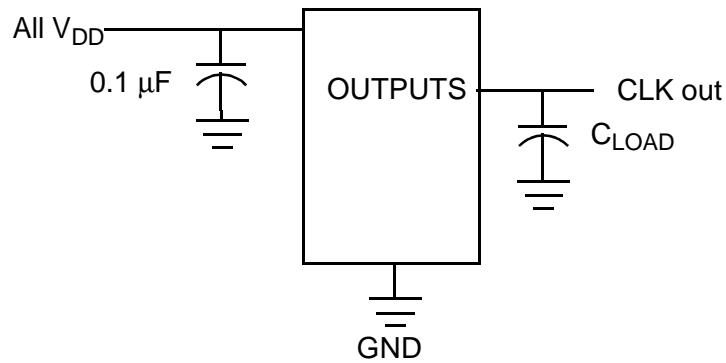


Figure 11. CMOS Output Test Circuits

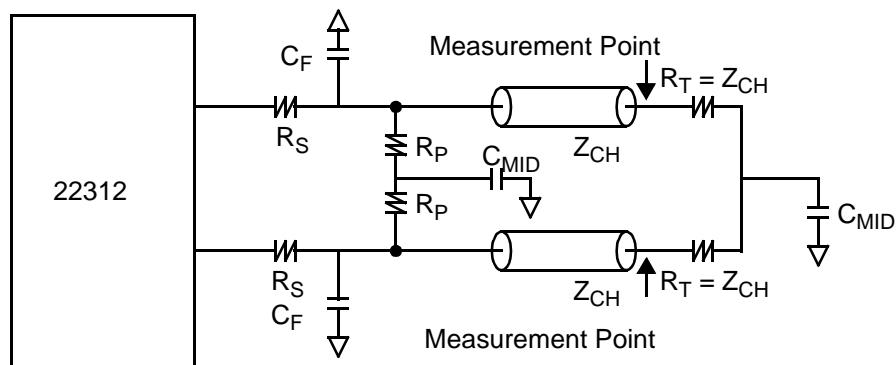
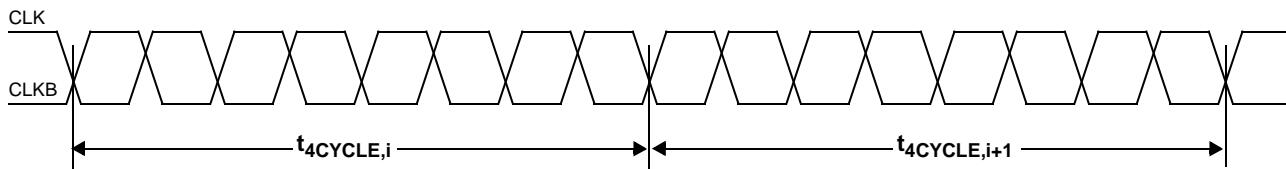


Figure 12. RCLK Test Circuit



Figure 13 shows the definition of 4-cycle short-term jitter. Short-term jitter is defined with respect to the falling edge of the CLK. 4-cycle short-term jitter is the difference between the cumulative cycle times of adjacent 4 cycles. Equal requirements apply for rising edges of the CLK signal. Equal require-

ments also apply for 2-cycle short-term jitter and 3-cycle short-term jitter, and for 5-cycle short-term jitter and 6-cycle short-term jitter.  $t_j$  is defined as the clock output short-term jitter over 2, 3, 4, 5, or 6 cycles.



$$t_J = t_{4CYCLE,i} - t_{4CYCLE,i+1} \text{ over 10000 consecutive cycles}$$

Figure 13. Short Term Jitter

Table 1. RCLK Test Circuit Component Values

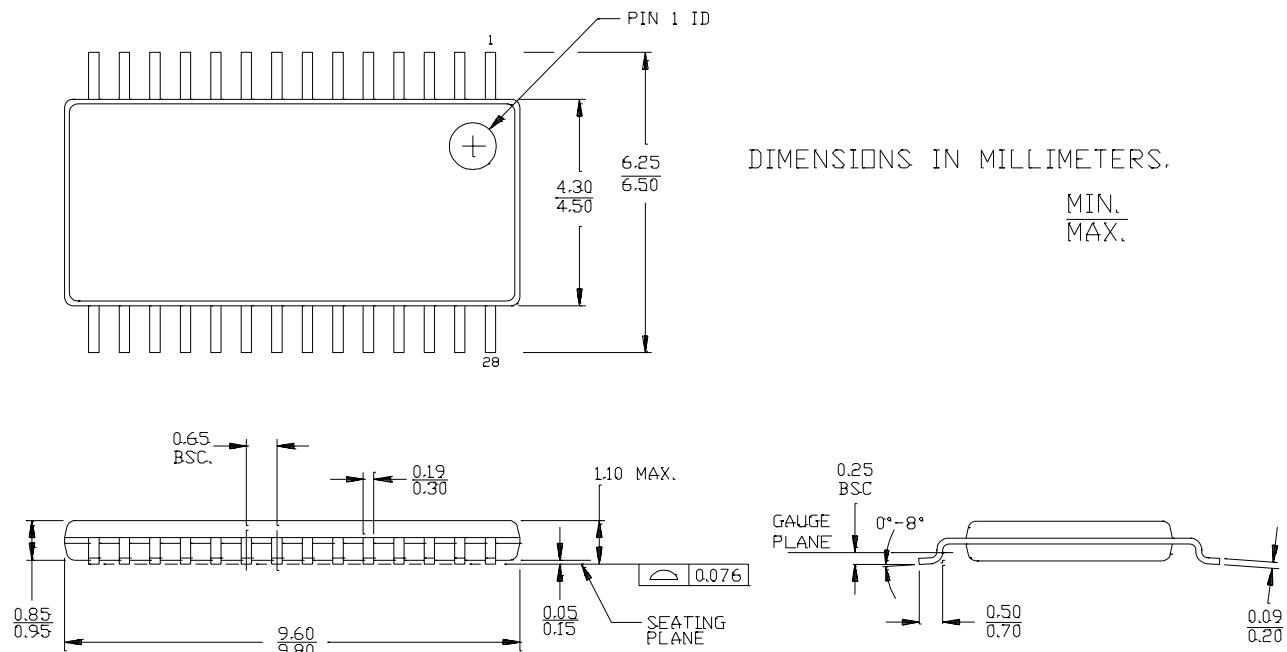
Symbol	Parameter	Value	Tolerance	Unit
$R_S$	Series Resistor	68	$\pm 5\%$	$\Omega$
$R_P$	Parallel Resistor	39	$\pm 5\%$	$\Omega$
$C_{MID}$	AC Ground Capacitor	0.01	$\pm 20\%$	$\mu F$

### Ordering Information

Ordering Code	Package Name	Package Type	Operating Range	Operating Voltages
CY22312ZC	Z29	28-TSSOP	Commercial ( $T_A=0^\circ C$ to $70^\circ C$ )	3.3V

## Package Diagram

**28-Lead Thin Shrunk Small Outline Package (4.40-mm Body) Z29**



51-85120

<b>Document Title:</b> CY22312 Two-PLL Clock Generator with Direct Rambus™ (Lite) Support <b>Document Number:</b> 38-07316				
REV.	ECN NO.	Issue Date	Orig. of Change	Description of Change
**	111465	03/01/02	JWK	New Data Sheet



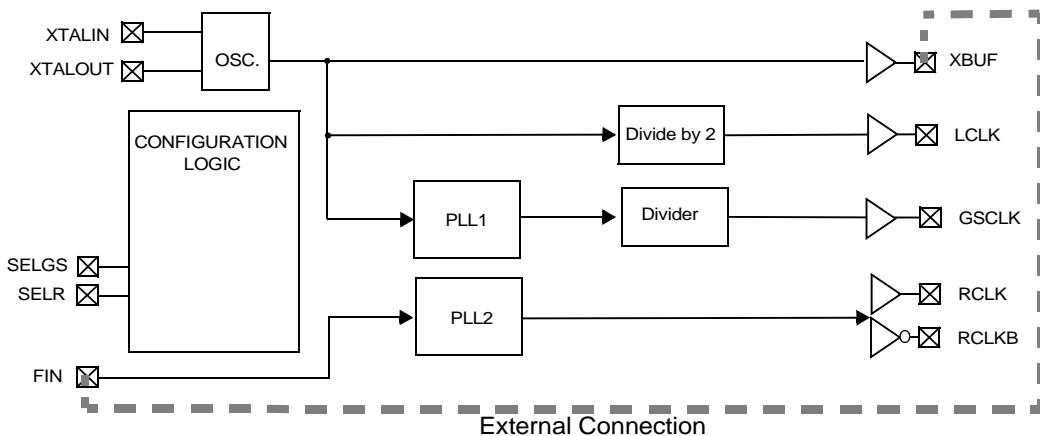
CYPRESS

CY22312

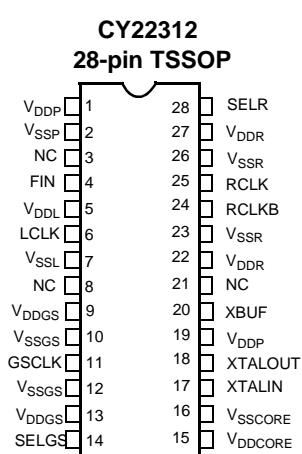
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<b>Ultra-accurate PLLs</b>	High performance even with difficult multiplier ratios
<b>Compatible crystal load capacitors</b>	Identical oscillator circuit to CY24141
<b>Direct Rambus™ clock support</b>	One pair of differential output drivers, identical specification to CY2212
<b>Two input selects</b>	Selectable 54.0/53.946 MHz output and 300/400 MHz Rambus® output
<b>3.3V core, 3.3V and 2.5V outputs</b>	Supports SONY output voltage requirements
<b>28-pin TSSOP package</b>	Industry-standard packaging saves on board space

### Logic Block Diagram



### Pin Configuration



### Frequency Select Tables

GSSEL	PPM	GSCLK	Unit
0	0	54	MHz
1	-1.000	53.94605395	MHz
RSEL	PPM	RCLK, RCLKB	Unit
0	0	294.912	MHz
1	0	393.216	MHz

**Pin Summary**

Name	Pin Numbers	Description
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V <sub>SSP</sub>	2	Ground
NC	3, 8, 21	No Connect (Reserved for Test Mode)
FIN	4	18.432-MHz input, must be externally connected to XBUF
V <sub>DDL</sub>	5	Power Supply for LCLK
LCLK	6	9.216-MHz output, FIN/2
V <sub>SSL</sub>	7	Ground
V <sub>DDGS</sub>	9, 13	Power Supply for GSCLK
V <sub>SSGS</sub>	10, 12	Ground
GSCLK	11	53.946-MHz/54-MHz output, frequency selectable with SELGS pin
SELGS	14	GSCLK Select Input, Internal Pull-Down Resistor, Referenced to V <sub>DDCORE</sub>
V <sub>DDCORE</sub>	15	Power Supply for Core
V <sub>SSCORE</sub>	16	Ground
XTALIN	17	Reference Crystal Input
XTALOUT	18	Reference Crystal Output
XBUF	20	Buffered Reference Output, must be externally connected to FIN
V <sub>DDR</sub>	22, 27	Power Supply for RCLK and RCLKB
V <sub>SSR</sub>	23, 26	Ground
RCLKB	24	Direct Rambus output (complement)
RCLK	25	Direct Rambus output
SELR	28	Direct Rambus PLL Multiplier Select Input, Internal Pull-Up Resistor, Referenced to V <sub>DDR</sub>

## Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

Supply Voltage ..... -0.5V to +4.0V

DC Input Voltage ..... -0.5V to + (V<sub>DD</sub> + 0.5V)

Storage Temperature ..... -65°C to +125°C

Static Discharge Voltage

(per MIL-STD-883, Method 3015) ..... 2000V

Latch up (per JEDEC 17) .....  $\geq \pm 200$  mA

## Operating Conditions<sup>[1]</sup>

Parameter	Description	Min.	Typ	Max.	Unit
V <sub>DDR</sub> , V <sub>DDCORE</sub> , V <sub>DDP</sub>	Supply Voltage for Core, Crystal Oscillator, and 3.3V outputs	3.15	3.45	3.6	V
V <sub>DDGS</sub> , V <sub>DDL</sub>	Supply Voltage for 2.5V outputs	2.25	2.5	2.75	V
T <sub>A</sub>	Operating Temperature, Ambient	0		+70	°C
C <sub>LOAD_OUT</sub>	Max. Load Capacitance, CMOS outputs			15	pF
f <sub>REF</sub>	External Reference Crystal		18.432		MHz

## Electrical Characteristics

Parameter	Description	Conditions	Min.	Typ.	Max.	Unit
I <sub>OH</sub>	Output High Current, 3.3V outputs <sup>[2]</sup>	V <sub>OH</sub> = V <sub>DD</sub> - 0.5, V <sub>DD</sub> = 3.3V	12	24		mA
	Output High Current, 2.5V outputs <sup>[2]</sup>	V <sub>OH</sub> = V <sub>DD</sub> - 0.5, V <sub>DD</sub> = 2.5V	8	16		mA
I <sub>OL</sub>	Output Low Current, 3.3V outputs <sup>[2]</sup>	V <sub>OL</sub> = 0.5V, V <sub>DD</sub> = 3.3V	12	24		mA
	Output Low Current, 2.5V outputs <sup>[2]</sup>	V <sub>OL</sub> = 0.5V, V <sub>DD</sub> = 2.5V	8	16		mA
C <sub>XTAL</sub>	Crystal Load Capacitance <sup>[2]</sup>	Total effective load of internal load caps		12.9		pF
C <sub>LOAD_IN</sub>	Input Pin Capacitance <sup>[2]</sup>	Except crystal pins		7		pF
V <sub>IH</sub>	HIGH-Level Input Voltage	CMOS levels, % of referenced power supply	70%			V <sub>DD</sub>
V <sub>IL</sub>	LOW-Level Input Voltage	CMOS levels, % of referenced power supply			30%	V <sub>DD</sub>
R <sub>I_GS</sub>	SELGS Input Resistor	Pull-down resistor on SELGS	80	100	135	kΩ
R <sub>I_R</sub>	SELR Input Resistor	Pull-up resistor on SELR	10		100	kΩ
I <sub>DD</sub>	Total Power Supply Current	Sum of all supply currents			120	mA

## Direct Rambus Electrical Characteristics<sup>[2]</sup>

Parameter	Description	Min.	Max.	Unit.
V <sub>CM</sub>	Differential output common-mode voltage	1.35	1.75	V
V <sub>X</sub>	Differential output crossing-point voltage	1.25	1.85	V
V <sub>COS</sub>	Output Voltage swing (p-p single-ended) <sup>[3]</sup>	0.4	0.7	V
V <sub>COH</sub>	Output high voltage		2.1	V
V <sub>COL</sub>	Output low voltage	1.0		V
r <sub>OUT</sub>	Output dynamic resistance (at pins) <sup>[4]</sup>	12	50	Ω

**Notes:**

1. Unless otherwise noted, Electrical and Switching Characteristics are guaranteed across these operating conditions.
2. Guaranteed by design, not 100% tested
3. V<sub>COS</sub> = V<sub>OH</sub> - V<sub>OL</sub>.
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## Switching Characteristics<sup>[2]</sup>

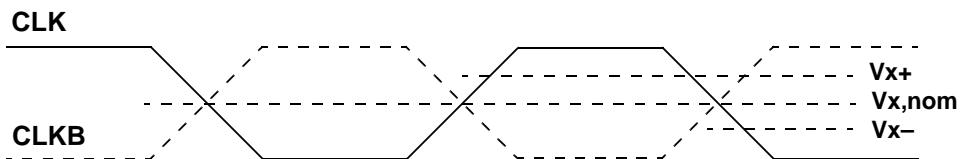
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		Over commercial temperature range <sup>[6]</sup>		±2	±5	PPM
DC	Output Duty Cycle	Duty cycle for all outputs, measured at V <sub>DD</sub> /2	45%	50%	55%	
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t <sub>4</sub>	Falling Edge Slew Rate	CMOS clock fall time, 20% to 80% of V <sub>DD</sub>	0.75	1.4		V/ns
t <sub>CR</sub> , t <sub>CF</sub>	Rise and Fall times	RCLK rise and fall time, 20% to 80% of V <sub>DD</sub>	160		400	ps
t <sub>CR-CF</sub>	Rise and Fall difference <sup>[7]</sup>	RCLK rise and fall time difference, 20% to 80% of V <sub>DD</sub>			100	ps
t <sub>5</sub>	Lock Time	PLL Lock Time from Power-up		1.0	3	ms

## Jitter Specifications<sup>[2]</sup>

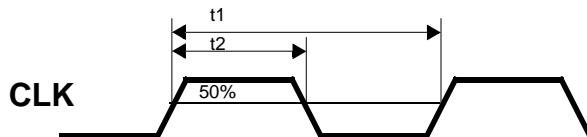
Parameter	Description	Conditions	Typ.	Max.	Unit
t <sub>6_XBUF</sub>	XBUF jitter <sup>[2]</sup>	Cycle-Cycle Jitter - 18.432 MHz		250	ps
t <sub>6_LCLK</sub>	LCLK jitter <sup>[2]</sup>	Cycle-Cycle Jitter - 9.216 MHz		250	ps
t <sub>6_GSCLK</sub>	GSCLK jitter <sup>[2]</sup>	Cycle-Cycle Jitter - 54 MHz, V <sub>DDGS</sub> = 2.25V - 2.75V		250	ps
		Cycle-Cycle Jitter - 53.946 MHz, V <sub>DDGS</sub> = 2.25V - 2.75V		250	ps
t <sub>7_XBUF</sub>	XBUF 1000 cycle jitter <sup>[2]</sup>	1000 Cycle-Cycle Jitter - 18.432 MHz		250	ps
t <sub>7_LCLK</sub>	LCLK 1000 cycle jitter <sup>[2]</sup>	1000 Cycle-Cycle Jitter - 9.216 MHz		250	ps
t <sub>7_GSCLK</sub>	GSCLK 1000 cycle jitter <sup>[2,8]</sup>	1000 Cycle-Cycle Jitter - 54 MHz, V <sub>DDGS</sub> = 2.25V - 2.75V		400	ps
		1000 Cycle-Cycle Jitter - 53.946 MHz, V <sub>DDGS</sub> = 2.25V - 2.75V		400	ps
t <sub>8</sub>	RCLK 1-6 cycle jitter <sup>[2,9]</sup>	Cycle-Cycle Jitter, 1-6 Cycles, 400 MHz		100	ps
		Cycle-Cycle Jitter, 1-6 Cycles, 300 MHz		140	ps
t <sub>9</sub>	RCLK Long-term jitter <sup>[2,10]</sup>	Long-term Jitter, 400 MHz		300	ps
		Long-term Jitter, 300 MHz		400	ps
t <sub>10</sub>	RCLK duty cycle error <sup>[2,11]</sup>	Cycle-Cycle Duty Cycle Error, 400 MHz		50	ps
		Cycle-Cycle Duty Cycle Error, 300 MHz		70	ps

**Notes:**

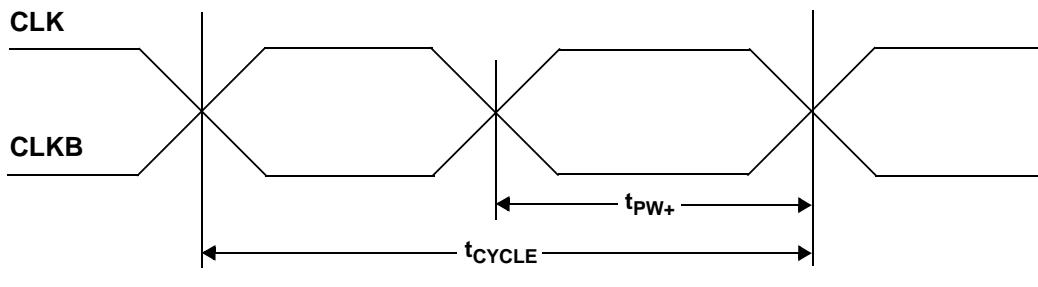
5. Tested across three lots on same board, PCB boards can vary more than ± 5 PPM.
6. Crystal should not be heated for this test, only IC.
7. Measured on same pin of a single device.
8. ± 4 Sigma, V<sub>DD</sub> = 3.3V.
9. Output short-term jitter specification is peak-to-peak and defined in *Figure 13*.
10. RCLK Long Term jitter shown in *Figure 9*.
11. RCLK Duty Cycle Error shown in *Figure 10*.



**Figure 1. RCLK Crossing Point Voltage**

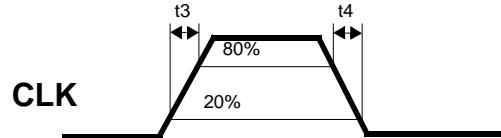


**Figure 2. CMOS Duty Cycle Definition**

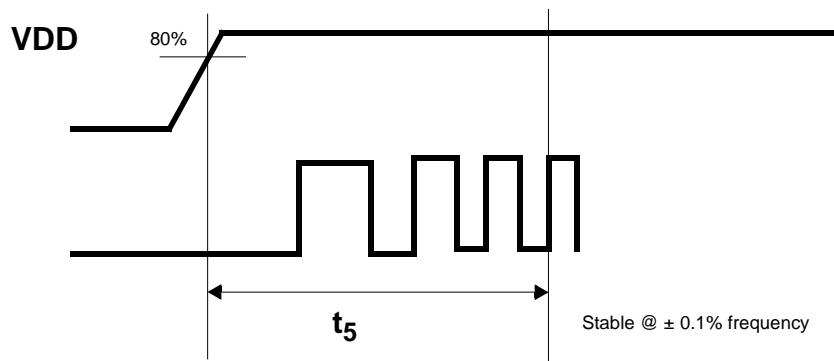


$$DC = t_{PW+}/t_{CYCLE}$$

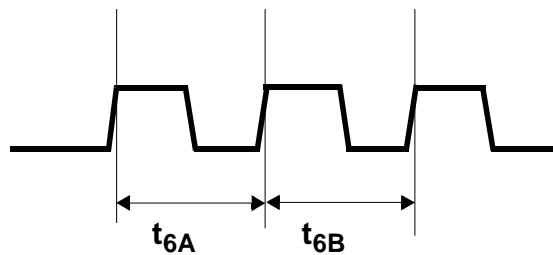
**Figure 3. RCLK Duty Cycle Definition**



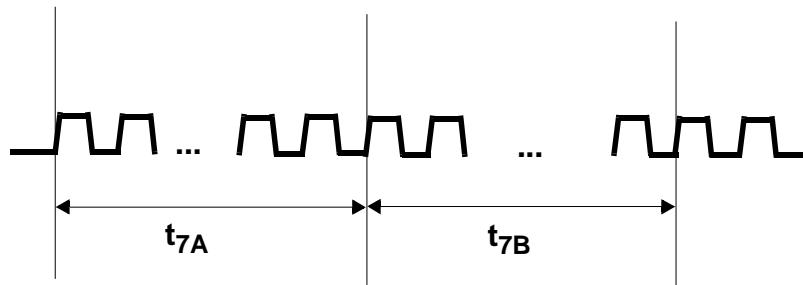
**Figure 4. Output Rise and Fall Time Definitions**



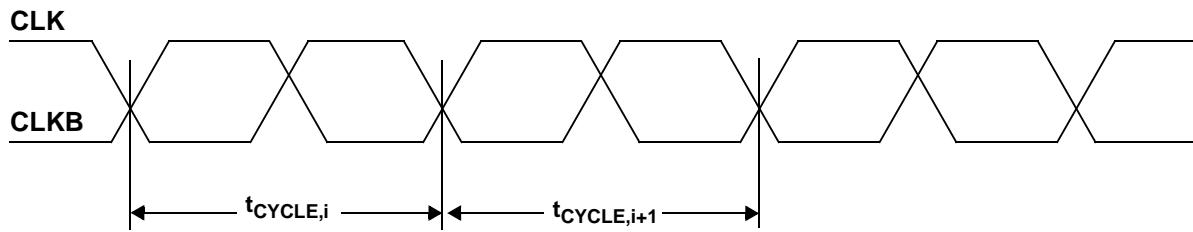
**Figure 5. PLL Lock Time**



**Figure 6. Cycle-to-Cycle Jitter**

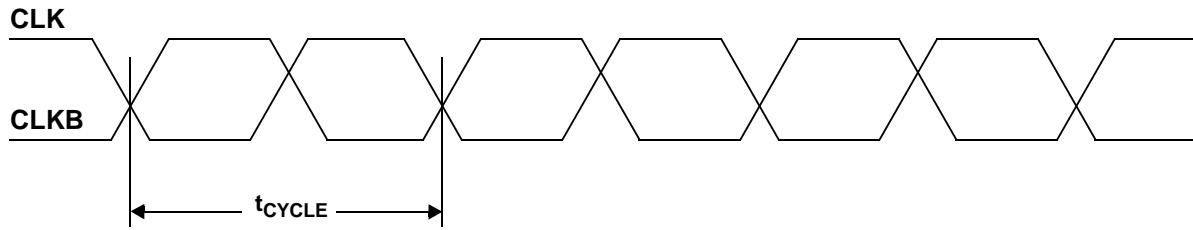


**Figure 7. 1000 Cycle Jitter**



$t_8 = t_{CYCLE,i} - t_{CYCLE,i+1}$  over 10000 consecutive cycles

**Figure 8. RCLK Cycle-to-Cycle Jitter**



$t_9 = t_{CYCLE,max} - t_{CYCLE,min}$  over 10000 cycles

**Figure 9. RCLK Long-term Jitter**

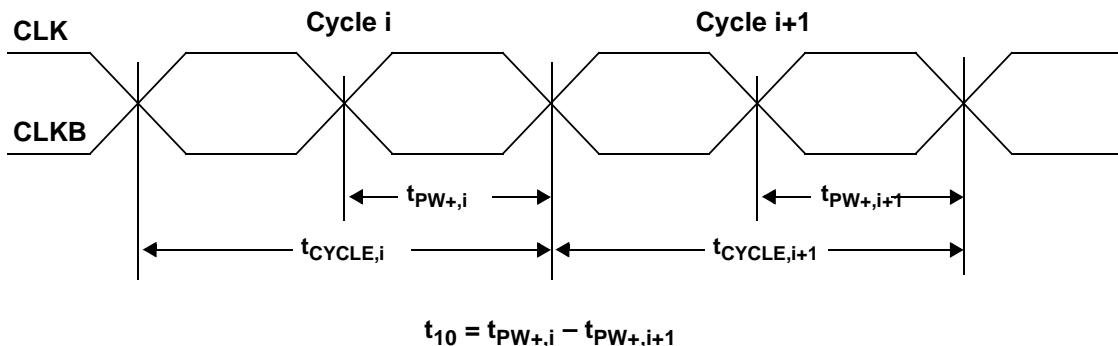


Figure 10. RCLK Duty Cycle Error

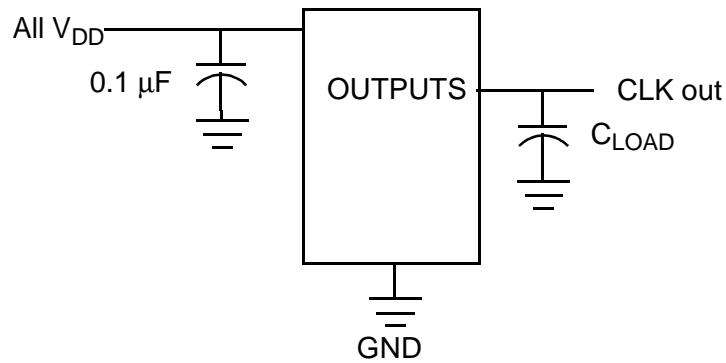


Figure 11. CMOS Output Test Circuits

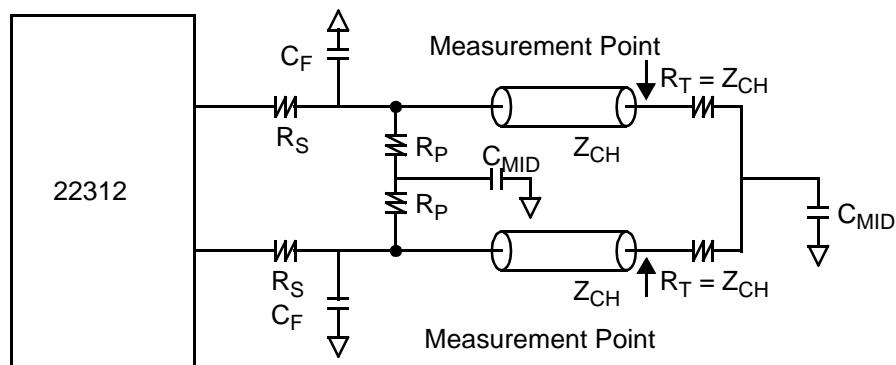
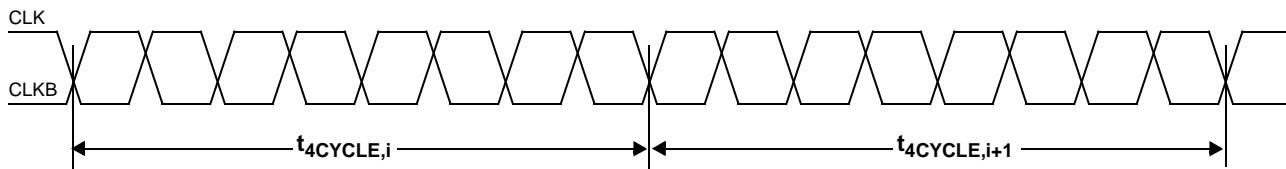


Figure 12. RCLK Test Circuit



Figure 13 shows the definition of 4-cycle short-term jitter. Short-term jitter is defined with respect to the falling edge of the CLK. 4-cycle short-term jitter is the difference between the cumulative cycle times of adjacent 4 cycles. Equal requirements apply for rising edges of the CLK signal. Equal require-

ments also apply for 2-cycle short-term jitter and 3-cycle short-term jitter, and for 5-cycle short-term jitter and 6-cycle short-term jitter.  $t_j$  is defined as the clock output short-term jitter over 2, 3, 4, 5, or 6 cycles.



$$t_J = t_{4CYCLE,i} - t_{4CYCLE,i+1} \text{ over 10000 consecutive cycles}$$

Figure 13. Short Term Jitter

Table 1. RCLK Test Circuit Component Values

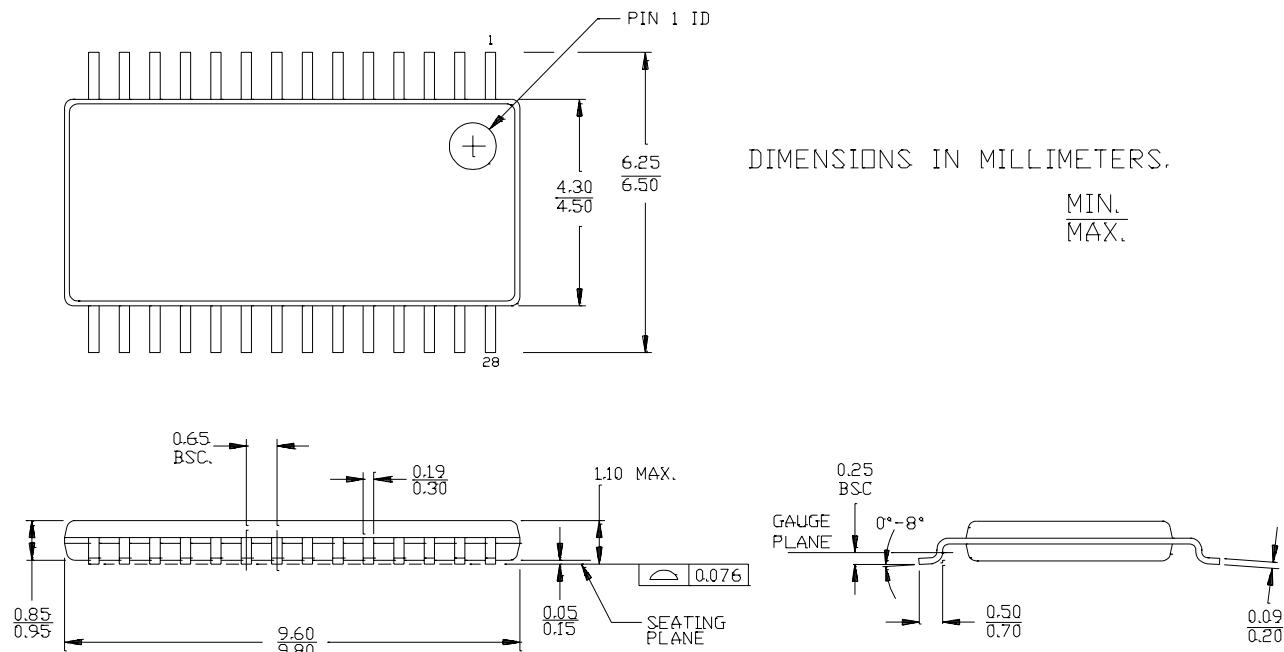
Symbol	Parameter	Value	Tolerance	Unit
$R_S$	Series Resistor	68	$\pm 5\%$	$\Omega$
$R_P$	Parallel Resistor	39	$\pm 5\%$	$\Omega$
$C_{MID}$	AC Ground Capacitor	0.01	$\pm 20\%$	$\mu F$

### Ordering Information

Ordering Code	Package Name	Package Type	Operating Range	Operating Voltages
CY22312ZC	Z29	28-TSSOP	Commercial ( $T_A=0^\circ C$ to $70^\circ C$ )	3.3V

## Package Diagram

**28-Lead Thin Shrunk Small Outline Package (4.40-mm Body) Z29**



<b>Document Title:</b> CY22312 Two-PLL Clock Generator with Direct Rambus™ (Lite) Support <b>Document Number:</b> 38-07316				
REV.	ECN NO.	Issue Date	Orig. of Change	Description of Change
**	111465	03/01/02	JWK	New Data Sheet